

<b>Notice of References Cited</b>	Application/Control No. 10/735,908		Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner Tran N. Nguyen		Art Unit 2834	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,745,318	05-1988	Ivanics, Laszlo	310/114
*	B	US-2003/0168925	09-2003	Bernreuther et al.	310/156.23
*	C	US-6,093,984	07-2000	Shiga et al.	310/26
*	D	US-6,703,740	03-2004	Klode, Harald	310/114
*	E	US-6,269,290	07-2001	Egami et al.	701/22
*	F	US-6,703,740	03-2004	Klode, Harald	310/114
*	G	US-4,227,105	10-1980	Kumakura, Shokichi	310/153
*	H	US-5,500,994	03-1996	Itaya, Hideki	29/598
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE19548117A1	12-1995	Germany		310-261
	O	JP-53-138005	12-1978	Japan	Imai et al	29/598
	P	JP-3-82350	04-1991	Japan	Kawai et al	310/156.08
	Q	JP-58-112449	07-1983	Japan	Umezawa et al	310/156.08
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.